

UNISONIC TECHNOLOGIES CO., LTD

1N70K-TA Preliminary Power MOSFET

1.2A, 700V N-CHANNEL POWER MOSFET

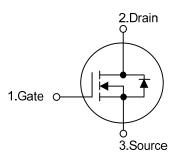
DESCRIPTION

The UTC **1N70K-TA** is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

■ FEATURES

- * $R_{DS(ON)}$ < 13.5 Ω @ V_{GS} = 10V, I_{D} = 0.5A
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

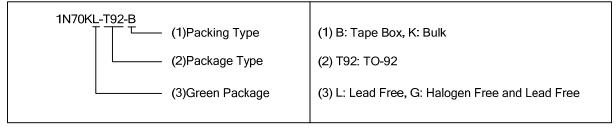




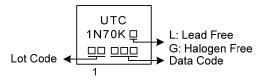
ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	- Package	1	2	3	Packing	
1N70KL-x-T92-B	1N70KG-x-T92-B	TO-92	G	D	S	Tape Box	
1N70KL-x-T92-K	1N70KG-x-T92-K	TO-92	G	D	S	Bulk	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



TO-92

www.unisonic.com.tw 1 of 5

■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	700	V
Gate-Source Voltage		V_{GSS}	±30	V
Continuous Drain Current	Continuous	I_{D}	1.0	Α
Pulsed Drain Current	Pulsed (Note 2)	I_{DM}	4.0	Α
Avalanche Current (Note 2)		I_{AR}	1.0	Α
Single Pulsed Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	5	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation		P_{D}	1.6	W
Junction Temperature		T_J	+150	°C
Storage Temperature		T_{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 10mH, I_{AS} = 1.0A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 1.0 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25 ^{\circ}C$.

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	140	°C/W	
Junction to Case	θ_{JC}	80	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

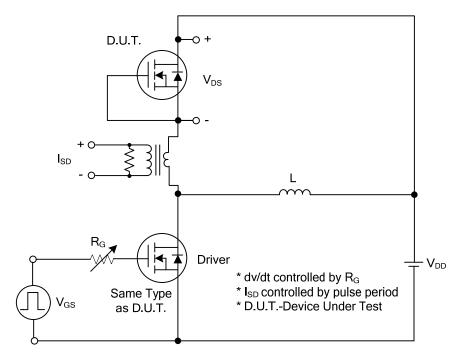
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700			V
Drain-Source Leakage Current		I _{DSS}	$V_{DS} = 700V, V_{GS} = 0V$			1	μΑ
Gate-Source Leakage Current	Forward	lass	$V_{GS} = 30V, V_{DS} = 0V$			100	nA
	Reverse	I _{GSS}	$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 0.5A$			13.5	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{ISS}			190		pF
Output Capacitance		Coss	V _{DS} =25V, V _{GS} =0V, f=1MHz		25		pF
Reverse Transfer Capacitance		C_{RSS}			10		pF
SWITCHING CHARACTERISTIC	S						
Rise Time (Note 1)		Q_G	V _{DS} =50V, V _{GS} =10V, I _D =1.3A,		14		nC
Turn-OFF Delay Time		Q_GS	I_{G} =100µA (Note 1, 2)		2.8		nC
Fall-Time		Q_GD	IG-100μΑ (Note 1, 2)		1		nC
Total Gate Charge (Note 1)		t _{D(ON)}			35		ns
Gate to Source Charge		t_R	V_{DD} =30V, V_{GS} =10V,		20		ns
Gate to Drain Charge		t _{D(OFF)}	$I_D = 0.5A, R_G = 25\Omega \text{ (Note 1, 2)}$		45		ns
Turn-ON Delay Time		t_{F}			8		ns
SOURCE- DRAIN DIODE RATIN	GS AND CHA	ARACTERIST	rics				
Maximum Body-Diode Continuous Current		I _S				1.0	Α
Maximum Body-Diode Pulsed Current		I _{SM}				4.0	Α
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =1.0A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time (Note 1)		t _{rr}	I _S =1.0A, V _{GS} =0V,		310		nS
Body Diode Reverse Recovery Charge		Q_{rr}	dI _F /dt=100A/µs		0.65		μC

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

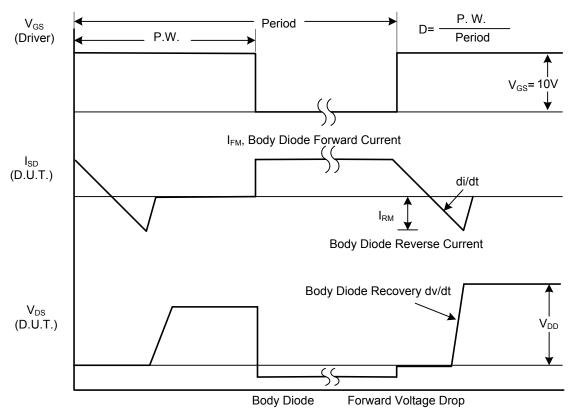
2. Essentially independent of operating temperature.



■ TEST CIRCUITS AND WAVEFORMS

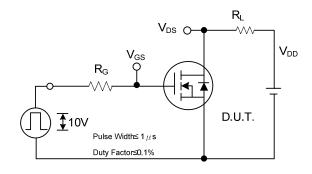


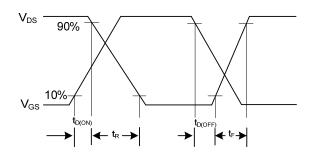
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

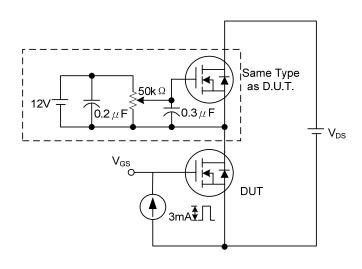
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

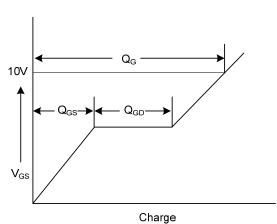




Switching Test Circuit

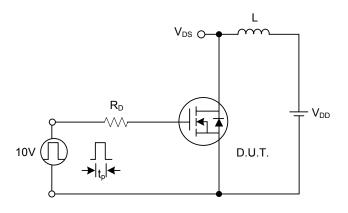
Switching Waveforms

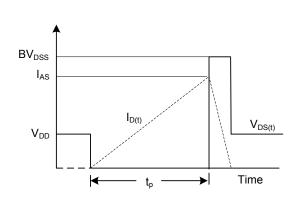




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. The information presented in this document does not form part of any quotation or contract, is believed to be accurate and reliable and may be changed without notice.

